Product data sheet

1. General description

WeEnPACK-B1 module with WeEn 1200V Gen2 SiC MOSFET and solder pin. NTC temperature sensor inside.



2. Features and benefits

- · 3-phase full bridge topology
- Noise filter integrated
- Solder pin configuration
- Low R_{DSon}
- Low Switching Losses
- Low Q_q and C_{rss}
- Low Inductive Design

3. Applications

- Power inverters
- AC-DC converters
- · Active power factor correctors
- Motor drives

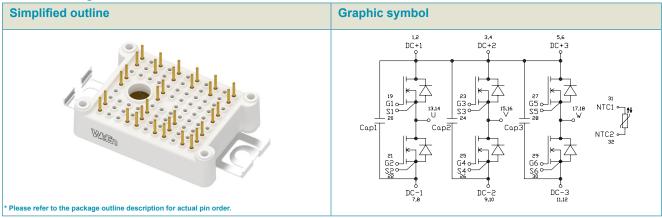
4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes	Values		Unit			
Absolute	Absolute maximum rating								
V _{DS}	drain-source voltage	T _j = 25 °C		1200			V		
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C			37		А		
P _{tot}	total power dissipation	T _h = 25 °C			72		W		
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit		
Static ch	aracteristics								
$R_{\text{DS(on)}}$	drain-source on-state resistance	$V_{GS} = 15 \text{ V}; I_D = 33 \text{ A}; T_j = 25 \text{ °C}$		-	40	-	mΩ		
Dynamic	characteristics								
$Q_{G(tot)}$	total gate charge	$I_D = 33 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	116	-	nC		
Q_{GD}	gate-drain charge	T _j = 25 °C		-	19	-	nC		
Source-d	Source-drain diode								
Q _r	recovered charge	I_{SD} = 33 A; V_{GS} = -4 V/18 V; V_{R} = 600 V; di/dt = 2000 A/μs; $R_{G(ext)}$ = 2 Ω; T_{j} = 25 °C		-	1940	-	nC		

5. Pinning information

Table 2. Pinning information



6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	3	Package issue date
WMSC040S12B1S-C	WeEnPACK-B1	WMSC040S12B1S-C6T	Tray	16	WeEnPACK- B1PSB-C	28-Jun-2024

7. Marking

Table 4. Marking codes

Type number	Marking codes
WMSC040S12B1S-C	WMSC040S12B1S-C

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter	Conditions	Notes	Values	Unit
storage temperature			-40 to 125	°C
operating junction temperature			-40 to 150	°C
maximum junction temperature	Intermittent condition with shortened lifetime		-40 to 175	°C
RMS isolation voltage	T _j = 25 °C; all terminals shorted; f = 50 Hz; t = 1 s		3500	V
drain-source voltage	T _j = 25 °C		1200	V
gate-source voltage	Absolute maximum values		-12 to 24	V
gate-source voltage	Recommended operational values		-4 to 18	V
total power dissipation	T _h = 25 °C		72	W
drain current	V _{GS} = 18 V; T _h = 25 °C		37	Α
	V _{GS} = 18 V; T _h = 100 °C		23	А
peak drain current	pulsed; tp \leq 10 us; T _h = 25 °C		70	Α
single pulse drain-to- source avalanche	I_{AS} = 24 A; L = 1 mH; V_{DD} = 100 V; $T_{j(\text{nit})}$ = 25 °C; per MOSFET		288	mJ
е		'		
DC body diode forward current	T _h = 25 °C; V _{GS} = -4 V		12	Α
Pulse body diode current	verified by design, tp limited by T _{jmax}		70	Α
	storage temperature operating junction temperature maximum junction temperature RMS isolation voltage drain-source voltage gate-source voltage gate-source voltage total power dissipation drain current peak drain current single pulse drain-to-source avalanche e DC body diode forward current			

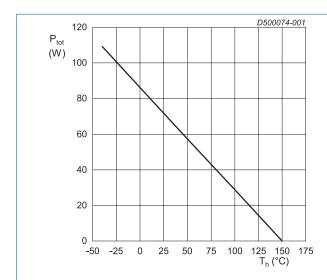


Fig. 1. Power dissipation as a function of heatsink temperature; maximum values

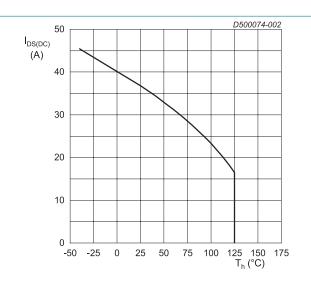


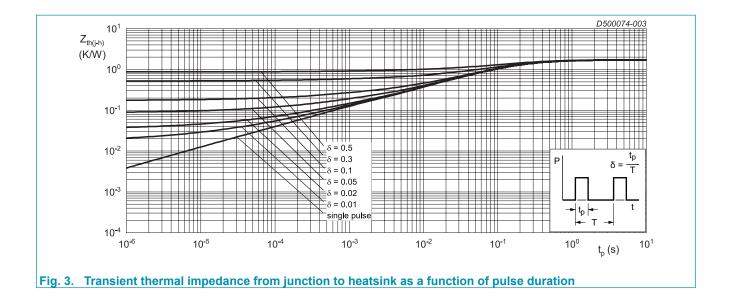
Fig. 2. Continuous Drain Current as a function of heatsink temperature

9. Thermal & Mechanical characteristics

Table 6. Thermal & Mechanical characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-c)}	thermal resistance from junction to case	per MOSFET		-	0.7	-	K/W
R _{th(j-h)}	thermal resistance from junction to heatsink	per MOSFET, $\lambda_{grease} = 1 \text{ W/(m·K)}$ thick _{grease} = 50 um		-	1.74	-	K/W
Internal Is	solation	basic insulation (class 1, IEC 61140)		Al ₂ O ₃			
d _{Creep}	Creepage distance	terminal to heatsink		-	11.5	-	mm
		terminal to terminal		-	6.3	-	mm
d _{Clear}	Clearance	terminal to heatsink		-	10	-	mm
		terminal to terminal		-	5	-	mm
СТІ	Comperative tracking index				>200		
F	Mounting force per clamp			20	-	50	N
G	Approximate Weight			-	20	-	g

Note: Module is ESD sensitive. Handling precautions are recommanded.

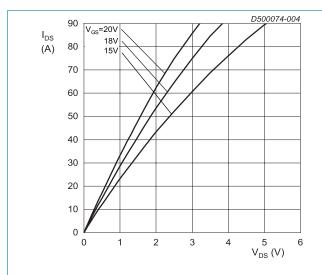


10. Characteristics

Table 7. Characteristics

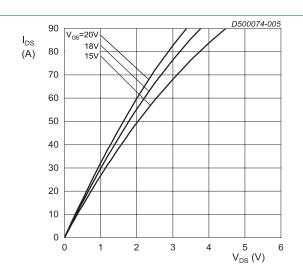
MOSFET Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
	aracteristics	Conditions	Notes	IVIIII	тур	IVIAX	Ullit
V _{(BR)DSS}	drain-source breakdown voltage	$I_D = 100 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$		1200	-	-	V
$V_{GS(th)}$	gate-source threshold	I _D = 10 mA; V _{DS} = 10 V; T _j = 25 °C		1.9	2.5	3.5	V
	voltage	I _D = 10 mA; V _{DS} = 10 V; T _j = 175 °C		-	1.9	-	V
I _{DSS}	drain leakage current	V _{DS} = 1200 V; V _{GS} = 0 V; T _j = 25 °C		-	0.2	100	μA
I _{GSS}	gate leakage current	V _{GS} = 24 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
	(absolute value)	V _{GS} = -12 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 33 A; T _j = 25 °C		-	40	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 33 A; T _j = 25 °C		-	33	45	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 125 °C		-	45	-	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 150 °C		-	53	-	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 175 °C		-	56	-	mΩ
R _G	gate resistance	f = 1 MHz; T _j = 25 °C; per MOSFET		-	0.8	-	Ω
g _{fs}	transconductance	V _{DS} = 20 V; I _D = 33 A; T _j = 25 °C		-	27	-	S
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 33 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	116	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C		-	42	-	nC
Q_{GD}	gate-drain charge			-	19	-	nC
C _{iss}	input capacitance	V _{DS} = 1000 V; V _{GS} = 0 V; f = 100 KHz;		-	2.45	-	nF
C _{oss}	output capacitance	T _j = 25 °C		-	108	-	pF
C _{rss}	reverse transfer capacitance			-	11	-	pF
E _{oss}	Coss stored energy			-	54	-	μJ
t _{d(on)}	turn-on delay time	V _{DS} = 800 V; V _{GS} = -4 V/18 V;		-	14	-	ns
t _r	rise time	$R_{G(ext)}$ = 2.4 Ω; I_D = 33 A; L = 100 μH; T_j = 25 °C		-	9	-	ns
$t_{d(off)}$	turn-off delay time	1		-	38	-	ns
t _f	fall time			-	17	-	ns
E _{on}	turn-on energy			-	406	-	μJ
E _{off}	turn-off energy			_	219	-	μJ

Body dic	ode						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
V_{SD}	source-drain voltage	$V_{GS} = -4 \text{ V}; I_F = 33 \text{ A}; T_j = 25 \text{ °C}$		-	5.5	-	V
		$V_{GS} = -4 \text{ V; } I_F = 33 \text{ A; } T_j = 150 \text{ °C}$		-	5.0	-	V
Dynamic	characteristics						
I _{rrm}	reverse recovery current	OB , CO , IX ,		-	48	-	А
t _{rr}	reverse recovery time	di/dt = 2000 A/ μ s; $R_{G(ext)}$ = 2 Ω ; T_j = 25 °C		-	65	-	ns
Q _r	recovered charge			-	1940	-	nC
E _{rec}	reverse recovery energy			-	1106	-	μJ
I _{rrm}	reverse recovery current	I _{SD} = 33 A; V _{GS} = -4 V/18 V; V _R = 600 V;		-	59	-	Α
t _{rr}	reverse recovery time	di/dt = 2400 A/μs; $R_{G(ext)}$ = 2 Ω; T_j = 150 °C		-	67	-	ns
Q _r	recovered charge			-	2360	-	nC
E _{rec}	reverse recovery energy			-	1368	-	μJ
Internal o	capacitance Specification	IS	l				
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
С	capacitance			-	22	-	nF
	rated voltage			-	1000	-	V
	operating temperature			-55	-	125	°C
NTC ther	mistor				'		
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R ₂₅	Rated resistance	T _{NTC} = 25 °C		-	5000	-	Ω
R ₁₀₀		T _{NTC} = 100 °C		493±5%		Ω	
B _{25/50}	B-value	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$		3380		K	
	Maximum operating temperature			-	200	-	°C
	Dissipation costant			-	2	-	mW/K
	Thermal time constant			-	≤10	-	s



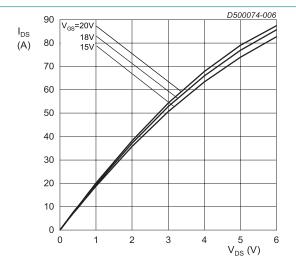
 $T_j = -40 \, ^{\circ}\text{C}; t_p < 200 \, \mu\text{s}$

Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values

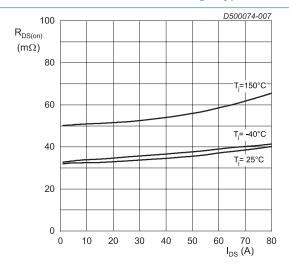


 $T_j = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

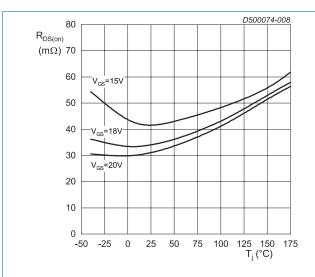
Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values



 T_j = 150 °C; t_p < 200 µs Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values

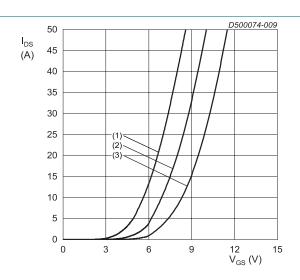


 V_{GS} = 18 V; t_p < 200 µs Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



 I_{DS} = 33 A; t_p < 200 μs

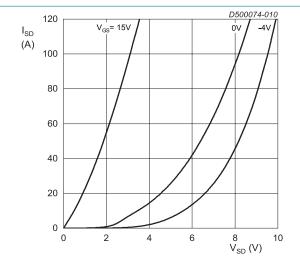
Fig. 8. Drain-source on-state resistance as a function of junction temperature



 $V_{DS} = 10 \text{ V; } t_p < 200 \text{ } \mu \text{s}$ (1) $T_j = 150 \text{ }^{\circ}\text{C}$ (2) $T_j = 25 \text{ }^{\circ}\text{C}$

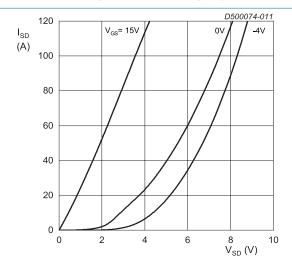
(3) $T_i = -40 \, ^{\circ}\text{C}$

Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values



 $T_{j} = -40 \, ^{\circ}\text{C}; t_{p} < 200 \, \mu\text{s}$ Fig. 10. Body diode forward characteristics;

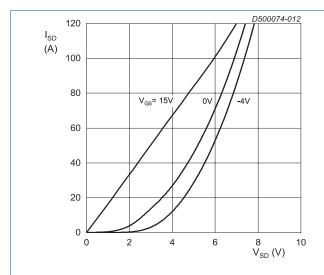
typical values



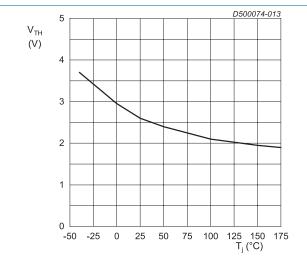
 $T_i = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

Fig. 11. Body diode forward characteristics; typical values

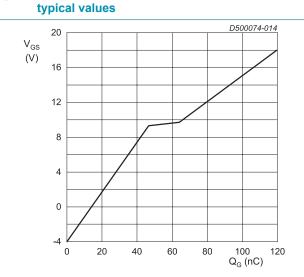
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 $T_{\rm j} = 150~{\rm ^{\circ}C};~t_{\rm p} < 200~\mu s$ Fig. 12. Body diode forward characteristics;



V_{DS} = 10 V; I_{DS} = 10 mA Fig. 13. Threshold voltage as a function of junction temperature



I_{DS} = 33 A; I_{GS} = 0.1 mA; V_{DS} = 800 V; T_j = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values

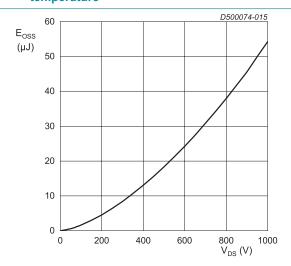
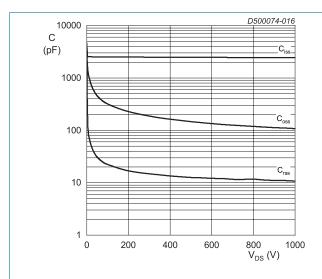
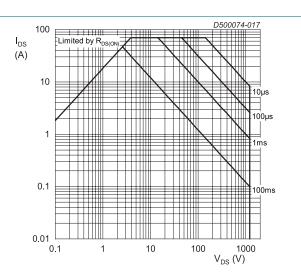


Fig. 15. Output capacitor stored energy as a function of drain-source voltage



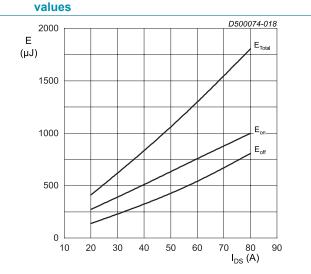
 $V_{DS} = 0 - 1000 \text{ V}$ T. = 25 °C: $V_{CS} = 25 \text{ mV}$: f = 100 k

T_j = 25 °C; V_{AC} = 25 mV; f = 100 KHz Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical



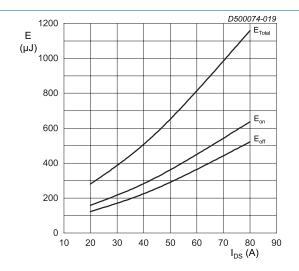
 $T_j = 25 \,^{\circ}\text{C}; D = 0$ Parameter: t_p

Fig. 17. Forward bias safe operating area



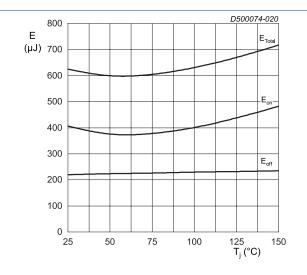
 T_j = 25 °C; V_{DD} = 800 V; $R_{G(ext)}$ = 2.4 $\Omega;$ $R_{G(on)}$ = 2.4 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

Fig. 18. Clamped Inductive Switching Energy as a function of drain current



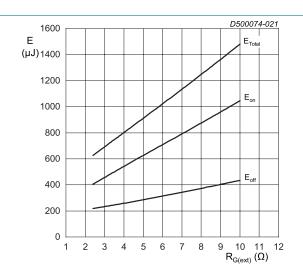
 T_{j} = 25 °C; V_{DD} = 600 V; $R_{G(off)}$ = 2.4 $\Omega;$ $R_{G(on)}$ = 2.4 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

Fig. 19. Clamped Inductive Switching Energy as a function of drain current



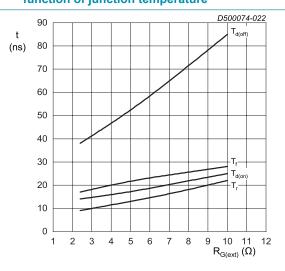
 I_{DS} = 33 A; V_{DD} = 800 V; $R_{G(off)}$ = 2.4 $\Omega;$ $R_{G(on)}$ = 2.4 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

Fig. 20. Clamped Inductive Switching Energy as a function of junction temperature



 T_{j} = 25 °C; V_{DD} = 800 V; I_{DS} = 33 A; V_{GS} = -4 V/18 V; L = 100 μH

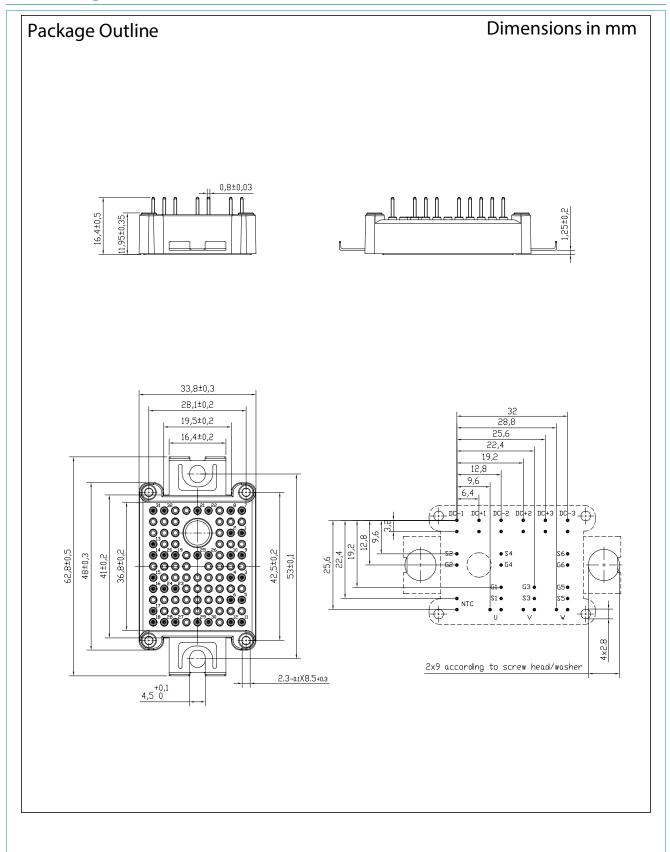
Fig. 21. Clamped Inductive Switching Energy as a function of external gate resistance



 T_{j} = 25 °C; V_{DD} = 800 V; I_{DS} = 33 A; V_{GS} = -4 V/18 V; L = 100 μH

Fig. 22. Switching time as a function of external gate resistance

11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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